

Monday 28 April

15:10

Updates on Simulations Session CMOS simulation and connection between device-level and electronics simulations 15:25-15:40 Other detectors/technologies/activities Speaker Tommaso Croci 15:40-15:55 Newly measured semiconductor properties 15:55-16:10 Radiation damage: validation with measurements and development of highfluence models 16:10-16:25 Time dependent electric/weighting field 16:25-16:40 Simulation tools development 16:40